

## **Quarterly Reliability Monitoring Results**

## Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number						
		PZU5.6B1A-Q						
		Part Description						
		Nexperia DHAM	Zener					
		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113						
		Bake Tamb = 125 °C	24 hours					
" * 4	PC	Soak Tamb = 85 °C, RH = 85%	168 hours	1160		•		
# A1	Preconditioning	Reflow soldering	3 cycles	1168	66640	0		
	UTDD	MIL-STD-750-1						
	HIGH Tomporature Poverse	M1038 Method A Tj = Tjmax, VR = 80 % of rated reverse						
# B1	Bias	voltage	1000 hours	198	11960	0		
# BI	ыцэ		1000 110015	190	11900	0		
		MIL-STD-750-1 M1038 Method B						
	SSOP	Tj = Tjmax, Iz = 100% of max. datasheet						
# B1b	Steady State Operational	reverse current	1000 hours	24	1760	0		
	, ,							
	тс	JESD22-A104						
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	240	14800	0		
	UHAST	JESD22-A118						
# A3 <b>or</b>	Unbiased HAST	Tamb = 130 °C, RH = 85 %	96 hours	240	14800	0		
		JESD22-A102	50 Hours	240	14000	0		
	AC	Tamb = 121 °C, RH = 100 %						
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)						
	H3TRB	JESD22-A101						
" AO II	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of	10001	240	1 1000			
# A2 alt	Temperature Reverse Bias	rated reverse voltage <sup>[1]</sup>	1000 hours	240	14800	0		
		MIL-STD-750 Method 1037						
# A.F	IOL	ton = toff, devices powered to insure $\Delta Tj$ =	1000 5	264	16720	0		
# A5	Intermittent Operating Life	100 -C 101, 12000 cycles	1000 hours	264	16720	0		
	RSH	JESD22-A111						
# C8	Resistance to Solder Heat		10 s	184	5520	0		
# 00	SD	200 0 = 3 0	10.2	104	3320	U		
# C10	Solderability	J-STD-002		501	5010	0		
7 010	Co.acrabiney	3 3.5 305		201	2010	U		

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Zener	11960	0	0,36	2,82E+09

© 2023 Nexperia B.V.

All information hereunder is per Nexperia's best knowledge. This document does not provide for any representation or warranty express or implied by Nexperia. In case Nexperia has tested the product, this documentation reflects the outcome of the analysis of the actually tested parts only.

nexperia.com